

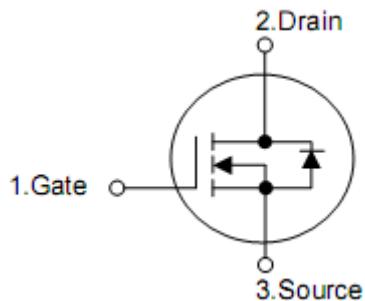
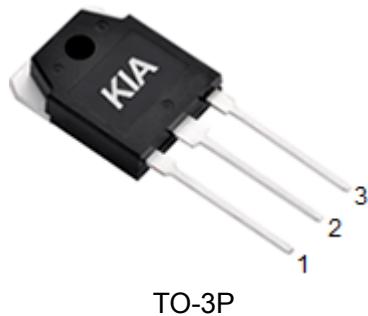
1. Features

- Proprietary New Planar Technology
- $R_{DS(ON)}=45m\Omega$ (typ.)@ $V_{GS}=10V$
- Low Gate Charge Minimize Switching Loss
- Fast Recovery Body Diode

2. Applications

- DC-DC Converters
- DC-AC Inverters for UPS
- SMPS and Motor controls

3. Pin configuration



Pin	Function
1	Gate
2	Drain
3	Source

4. Ordering Information

Part Number	Package	Brand
KNH3625A	TO-3P	KIA

5. Absolute maximum ratings

($T_c = 25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Ratings	Unit
Drain-to-Source Voltage ¹⁾	V_{DSS}	250	V
Gate-to-Source Voltage	V_{GSS}	± 20	V
Continuous Drain Current	I_D	60	A
	I_D	30	A
Pulsed Drain Current at $V_{GS}=10\text{V}$ ²⁾	I_{DM}	200	A
Single Pulse Avalanche Energy	EAS	1250	mJ
Peak Diode Recovery dv/dt ³⁾	dv/dt	5.0	V/ns
Power Dissipation	P_D	278	W
Derating Factor above 25°C	P_D	1.0	W/ $^\circ\text{C}$
Maximum Temperature for Soldering Leads at 0.063in (1.6mm) from Case for 10 seconds, Package Body for 10 seconds	T_L T_{PAK}	300 260	$^\circ\text{C}$
Operating and Storage Temperature Range	$T_J \& T_{STG}$	-55 to 150	$^\circ\text{C}$

Caution: Stresses greater than those listed in the "Absolute Maximum Ratings" may cause permanent damage to the device.

6. Thermal characteristics

Parameter	Symbol	Ratings	Unit
Thermal Resistance, Junction-to-Case	$R_{\theta JC}$	0.45	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction-to-Ambient	$R_{\theta JA}$	50	$^\circ\text{C}/\text{W}$

7. Electrical characteristics

($T_J=25^\circ\text{C}$, unless otherwise specified)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Drain-to-Source Breakdown Voltage	BV_{DSS}	$V_{\text{GS}}=0\text{V}, I_{\text{D}}=250\mu\text{A}$	250	-	-	V
Drain-to-Source Leakage Current	I_{DSS}	$V_{\text{DS}}=250\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$V_{\text{DS}}=200\text{V}, T_J=125^\circ\text{C}$	-	-	100	μA
Gate-to-Source Leakage Current	I_{GSS}	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Drain-to-Source ON Resistance ⁴⁾	$R_{\text{DS(ON)}}$	$V_{\text{GS}}=10\text{V}, I_{\text{D}}=25\text{A}$	-	45	60	$\text{m}\Omega$
Gate Threshold Voltage	$V_{\text{GS(TH)}}$	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{D}}=250\mu\text{A}$	2.0	-	4.0	V
Forward Transconductance ⁴⁾	g_{fs}	$V_{\text{DS}}=15\text{V}, I_{\text{D}}=20\text{A}$	-	65	-	S
Input Capacitance	C_{iss}	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=25\text{V}, f=1.0\text{MHz}$	-	4020	-	pF
Reverse Transfer Capacitance	C_{rss}		-	254	-	
Output Capacitance	C_{oss}		-	506	-	
Total Gate Charge	Q_g	$V_{\text{DD}}=100\text{V}, I_{\text{D}}=20\text{A}, V_{\text{GS}}=0\sim 10\text{V}$	-	78	-	nC
Gate-to-Source Charge	Q_{gs}		-	27	-	
Gate-to-Drain (Miller) Charge	Q_{gd}		-	22	-	
Turn-on Delay Time	$t_{\text{d(ON)}}$	$V_{\text{DD}}=100\text{V}, I_{\text{D}}=20\text{A}, R_{\text{G}}=3.9\Omega, V_{\text{GS}}=10\text{V}$	-	22	-	nS
Rise Time	t_{rise}		-	32	-	
Turn-Off Delay Time	$t_{\text{d(OFF)}}$		-	68	-	
Fall Time	t_{fall}		-	26	-	
Continuous Source Current ⁴⁾	I_{SD}	Integral PN-diode in MOSFET	-	-	50	A
Pulsed Source Current ⁴⁾	I_{SM}		-	-	200	A
Forward Voltage	V_{SD}	$I_{\text{S}}=40\text{A}, V_{\text{GS}}=0\text{V}$	-	-	1.5	V
Reverse recovery time	t_{rr}	$V_{\text{GS}}=0\text{V}, I_{\text{F}}=20\text{A}, \text{di}I/\text{dt}=100\text{A}/\mu\text{s}$	-	180	-	ns
Reverse recovery charge	Q_{rr}		-	400	-	μC

Note:

- 1) $T_J=+25^\circ\text{C}$ to $+150^\circ\text{C}$
- 2) Repetitive rating; pulse width limited by maximum junction temperature.
- 3) $I_{\text{SD}}=20\text{A}$, $\text{di}/\text{dt}<100\text{ A}/\mu\text{s}$, $V_{\text{DD}}<\text{BV}_{\text{DSS}}$, $T_J=+150^\circ\text{C}$.
- 4) Pulse width $\leq 380\mu\text{s}$; duty cycle $\leq 2\%$.

8. Test circuits and waveforms

Figure 1. Maximum Transient Thermal Impedance

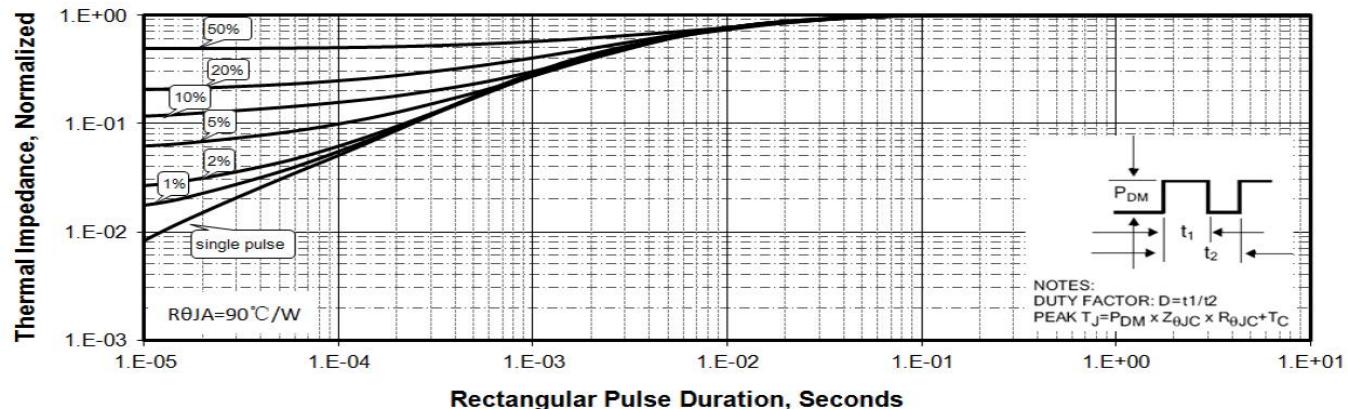


Figure 2 . Max. Power Dissipation vs Case Temperature

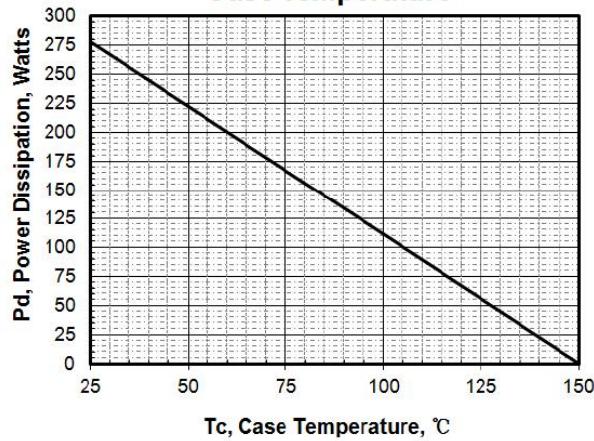


Figure 3 .Maximum Continuous Drain Current vs Tc

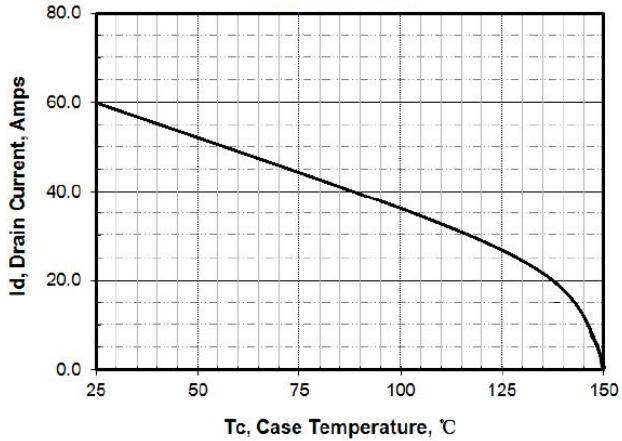


Figure 4. Output Characteristics

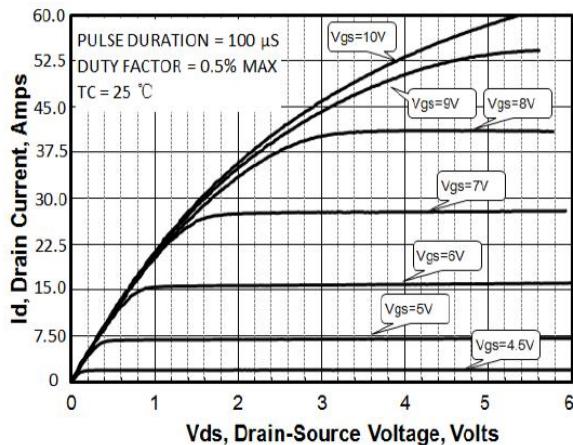


Figure 5. Rdson vs Gate Voltage

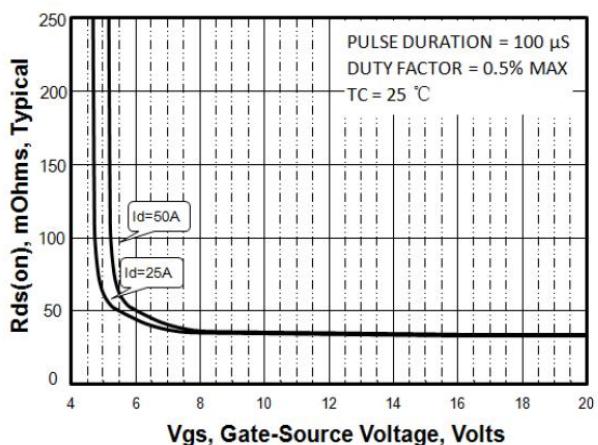


Figure 6. Peak Current Capability

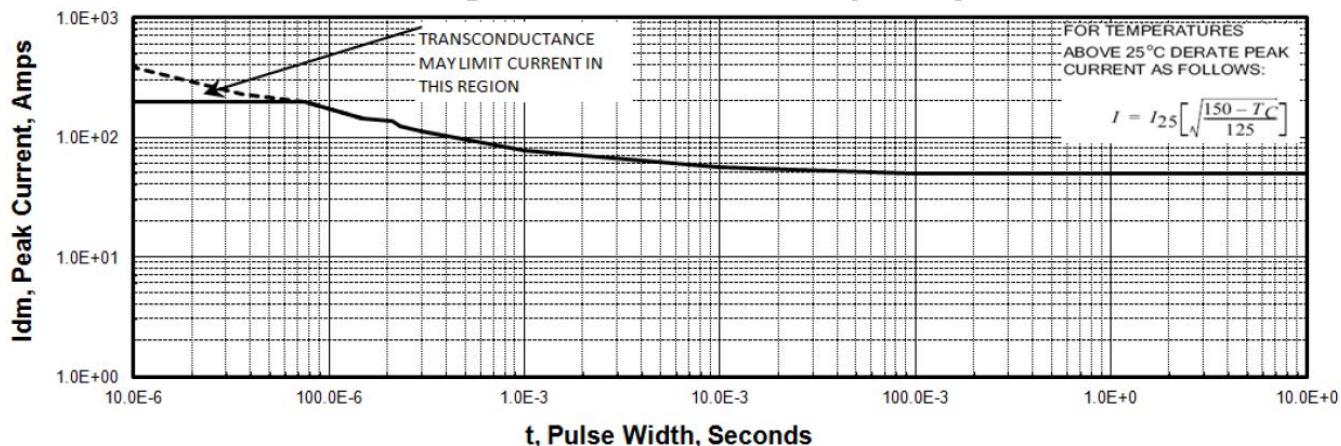


Figure 7. Transfer Characteristics

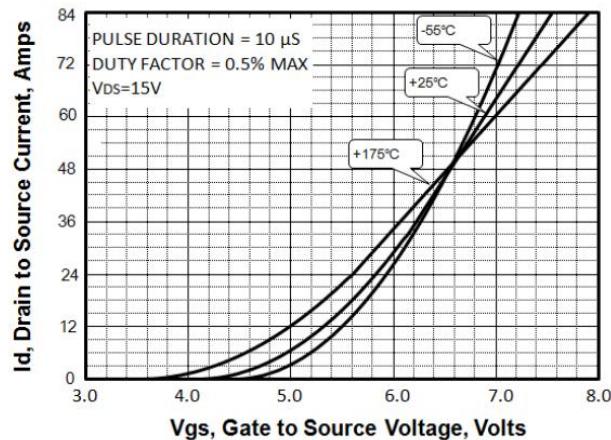


Figure 9. Drain to Source ON Resistance vs Drain Current

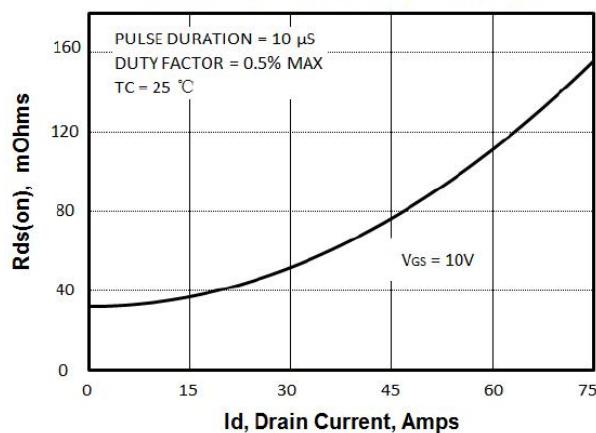


Figure 8. Unclamped Inductive Switching Capability

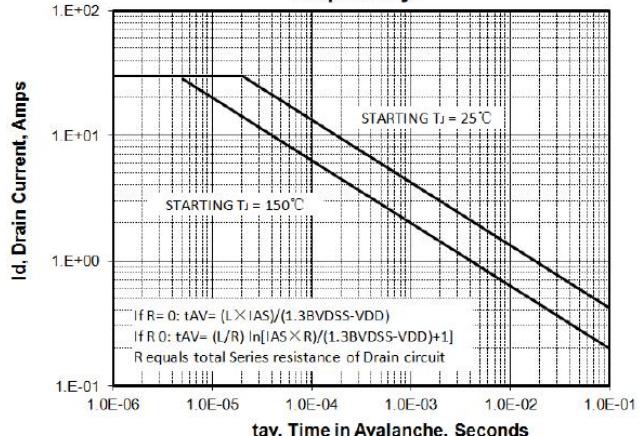
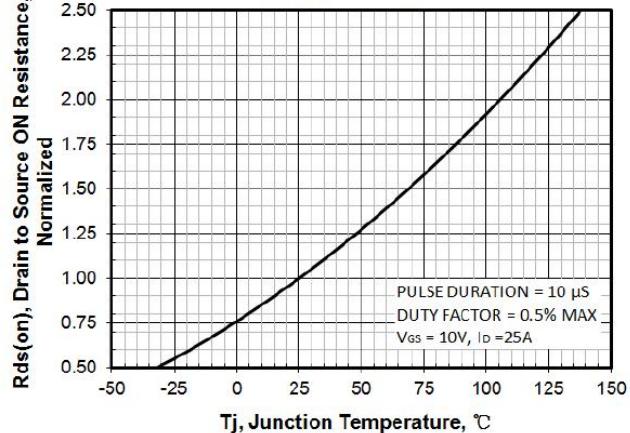
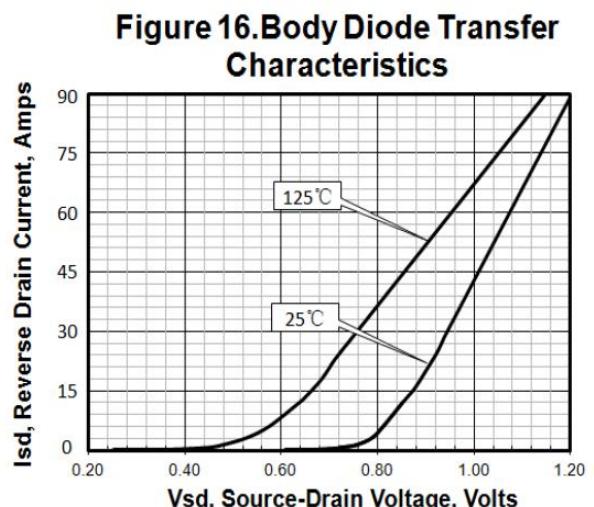
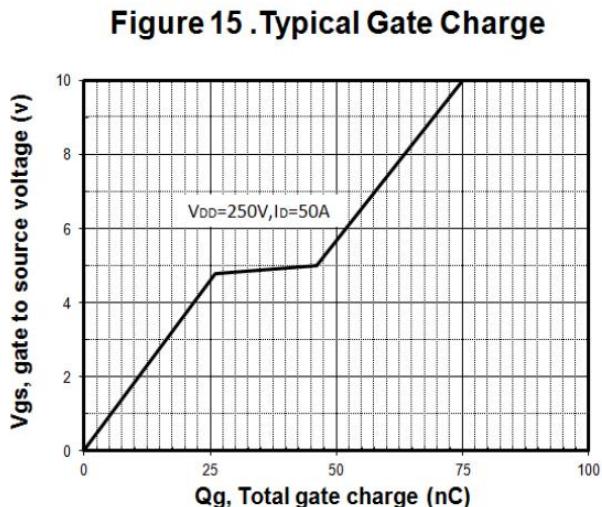
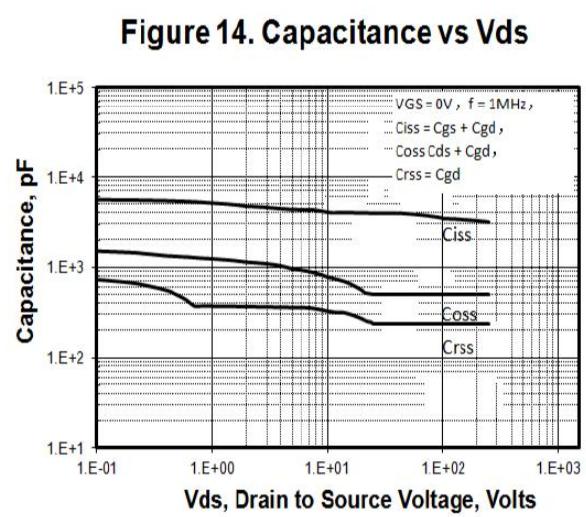
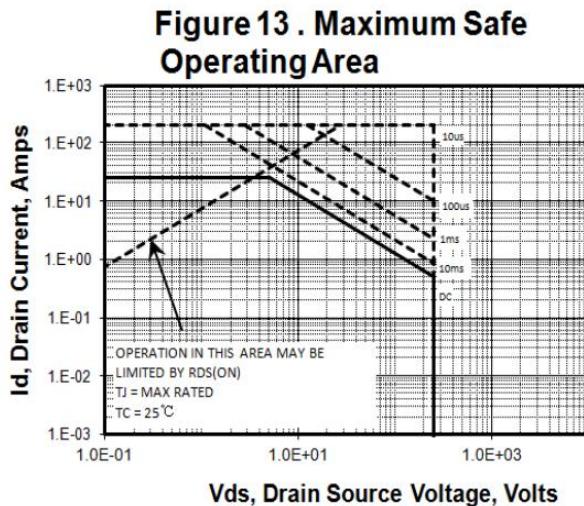
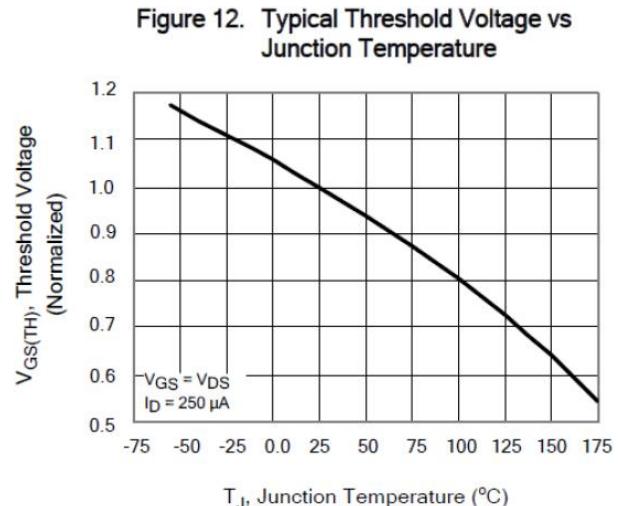
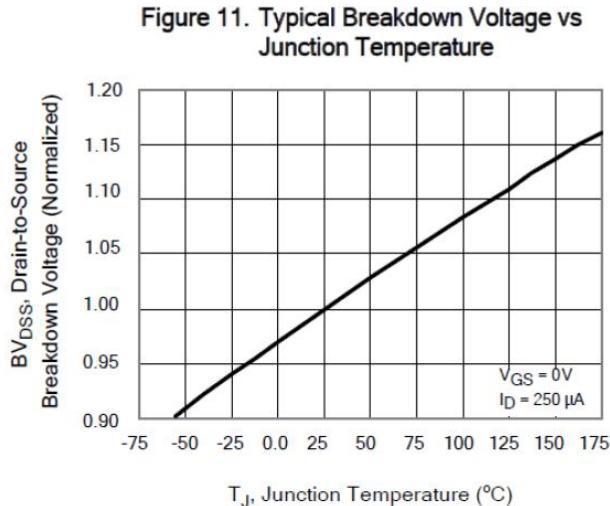


Figure 10. R_{dson} vs Junction Temperature





9. Test Circuits and Waveforms

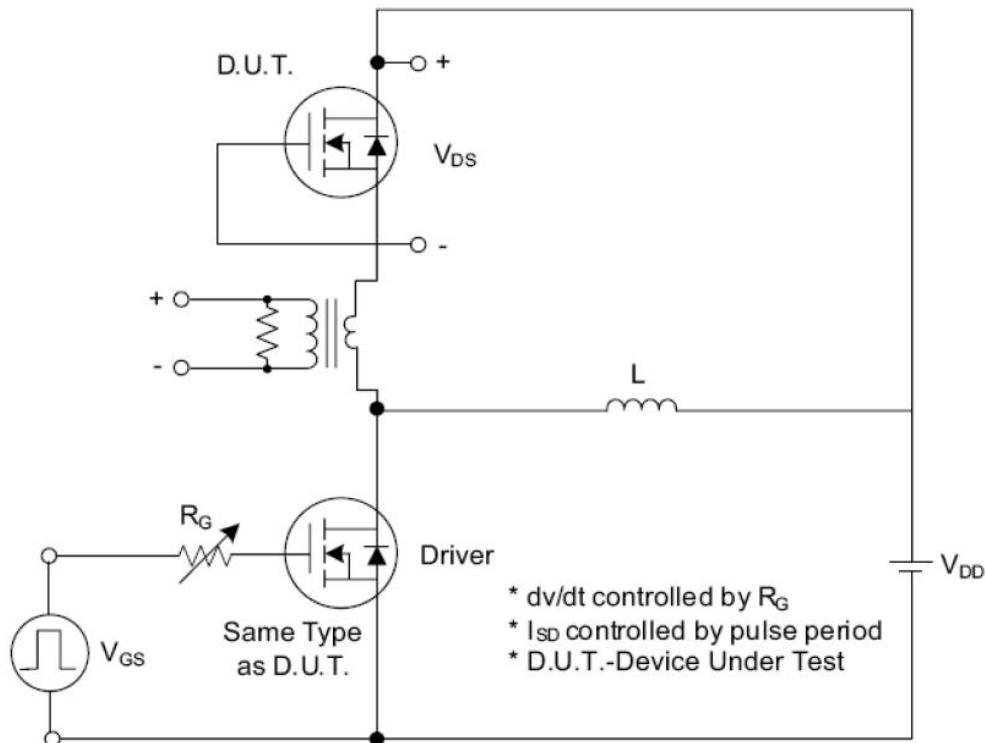


Fig. 1.1 Peak Diode Recovery dv/dt Test Circuit

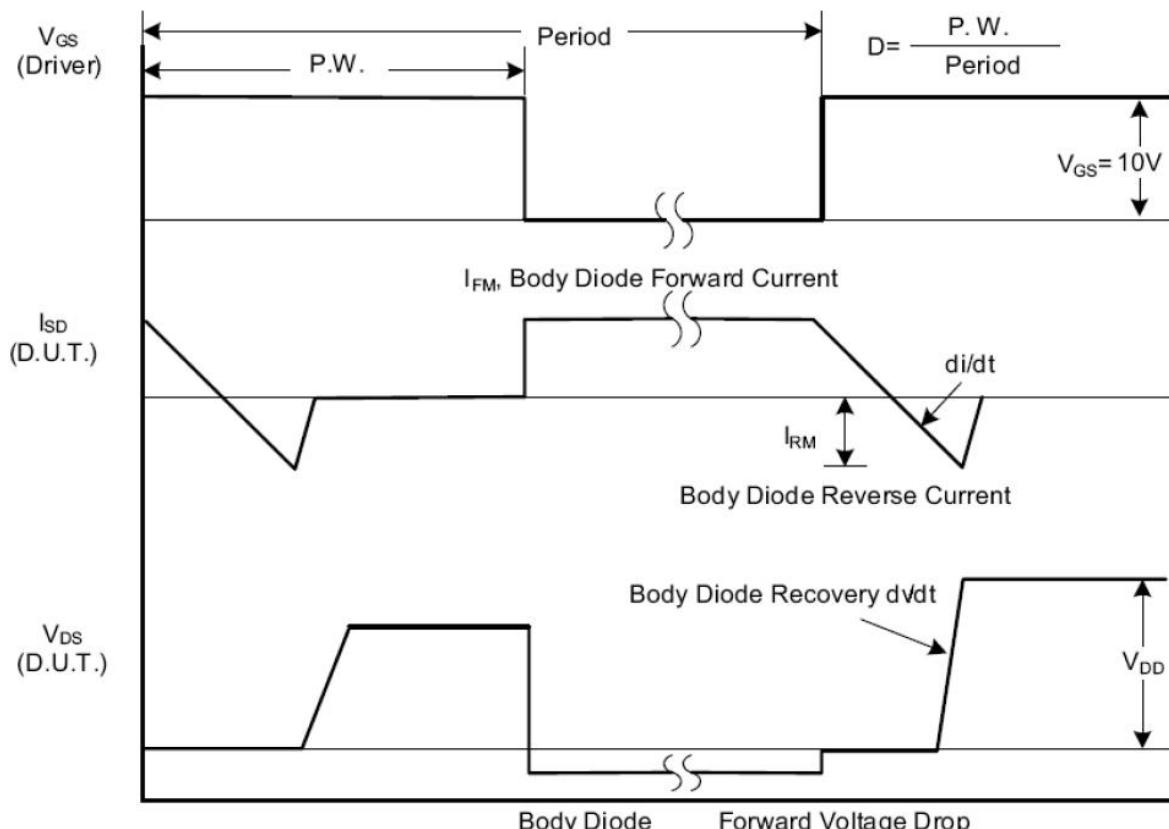


Fig. 1.2 Peak Diode Recovery dv/dt Waveforms

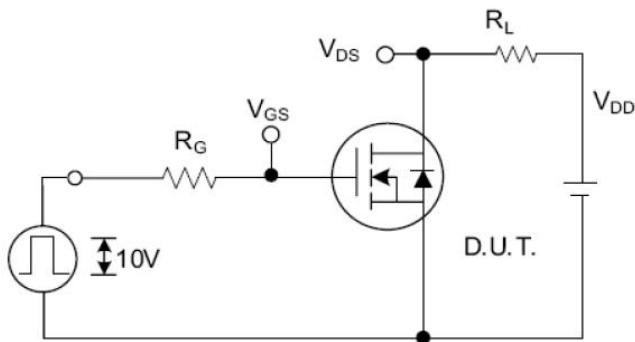


Fig. 2.1 Switching Test Circuit

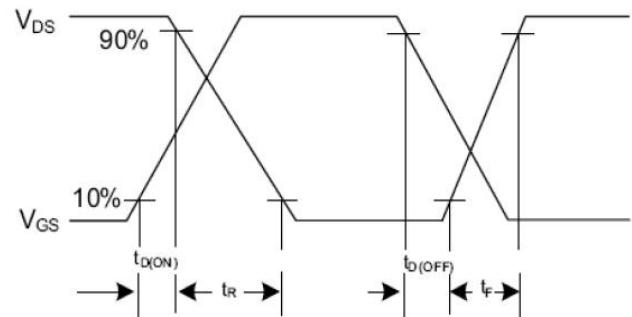


Fig. 2.2 Switching Waveforms

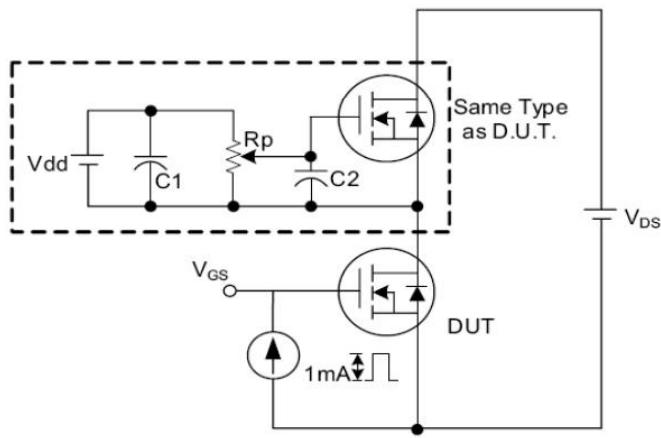


Fig. 3 . 1 Gate Charge Test Circuit

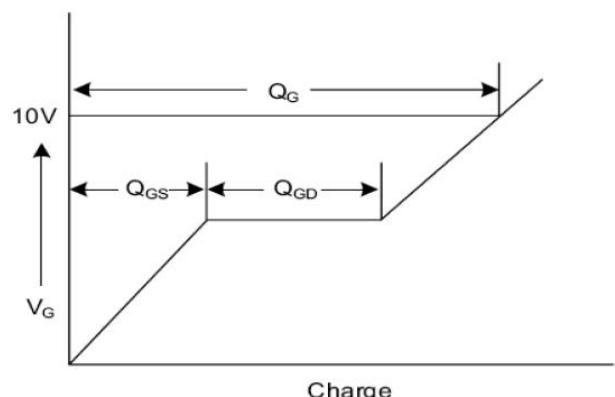


Fig. 3 . 2 Gate Charge Waveform

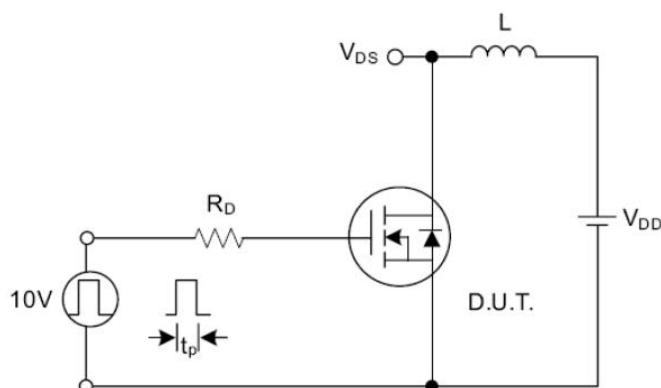


Fig. 4.1 Unclamped Inductive Switching Test Circuit

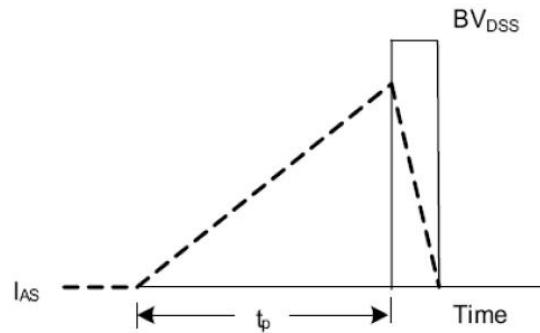


Fig. 4.2 Unclamped Inductive Switching Waveforms